

October 2008

FQB7N65C 650V N-Channel MOSFET

Features

- 7A, 650V, $R_{DS(on)}$ = 1.4 Ω @V_{GS} = 10 V Low gate charge (typical 28 nC)
- Low Crss (typical 12 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- · RoHS Compliant

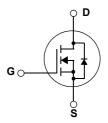


Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





Absolute Maximum Ratings

Symbol	Parameter		FQB7N65C	Units	
V _{DSS}	Drain-Source Voltage		650	V	
I _D	Drain Current - Continuous (T _C = 25°C)		7	А	
	- Continuous (T _C = 100°C)	4.45	А		
I _{DM}	Drain Current - Pulsed	(Note 1)	28	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	212	mJ	
I _{AR}	Avalanche Current	(Note 1)	7	А	
E _{AR}	Repetitive Avalanche Energy (Not		17.3	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		173	W	
	- Derate above 25°C		1.38	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purpose 1/8" from case for 5 seconds	300	°C		

Thermal Characteristics

Symbol	Parameter	FQB7N65C	Units		
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.75	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W		

Package Marking and Ordering Information

Device Marking Device		Package	Reel Size	Tape Width	Quantity
FQB7N65C	FQB7N65CTM	D2-PAK	330mm	24mm	800

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics			l .		
BV _{DSS}	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		650			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.8		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V			1	μА
		V _{DS} = 520 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	teristics					•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.5 A		1.2	1.4	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D =3.5 A (Note 4)		8		S
Dynamic Cl	haracteristics					•
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		955	1245	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		100	130	pF
C _{rss}	Reverse Transfer Capacitance			12	16	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 325 \text{ V}, I_D = 7\text{A},$		20	50	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		50	110	ns
t _{d(off)}	Turn-Off Delay Time	41.4.4.5		90	190	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		55	120	ns
Qg	Total Gate Charge	V _{DS} = 520 V, I _D = 7A,		28	36	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		4.5		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		12		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3		1	1	-11
I _S	Maximum Continuous Drain-Source Diode Forward Current				7	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				28	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 7 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 7 A,		400		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		3.3		μС

NOTES:

^{1.} Repetitive Rating : Pulse width limited by maximum junction temperature

^{2.} L = 8mH, I $_{AS}$ = 7A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C

^{3.} $I_{SD} \le$ 7A, di/dt \le 200A/ μ s, $V_{DD} \le$ BV $_{DSS}$, Starting T_J = 25°C

^{4.} Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$

^{5.} Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

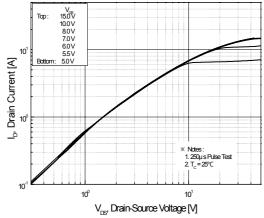


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

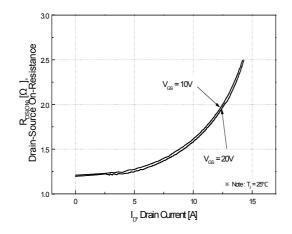


Figure 5. Capacitance Characteristics

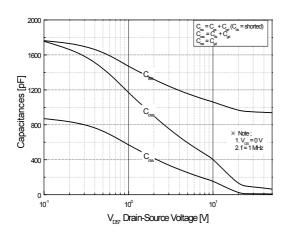


Figure 2. Transfer Characteristics

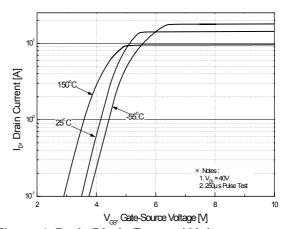


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

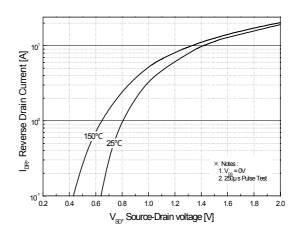
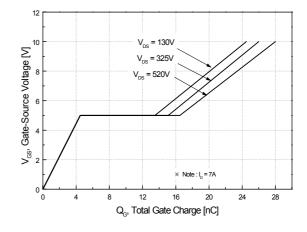


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

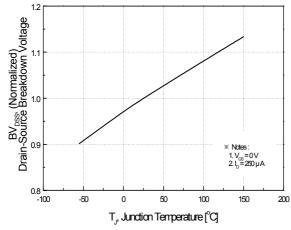


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature

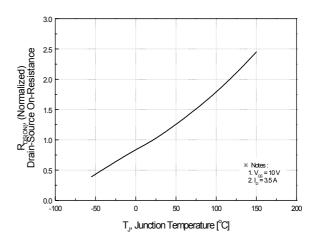
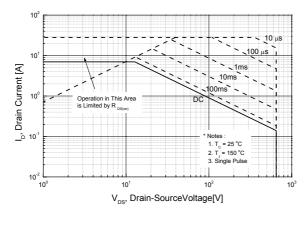


Figure 10. Maximum Drain Current vs. Case Temperature



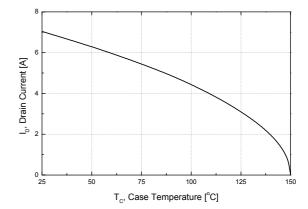
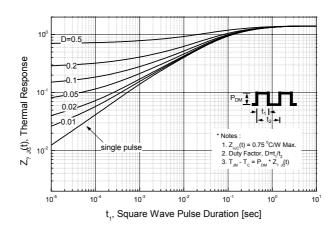
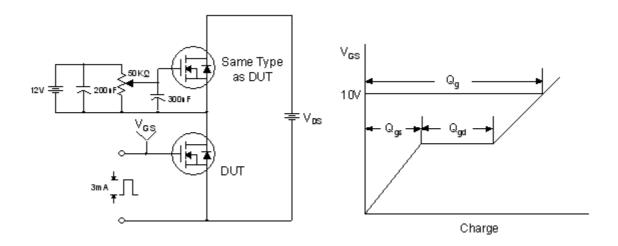


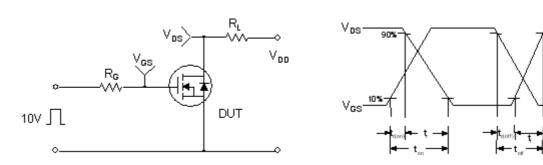
Figure 11. Transient Thermal Response Curve



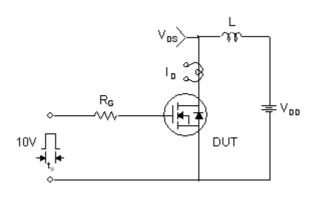
Gate Charge Test Circuit & Waveform

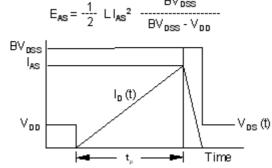


Resistive Switching Test Circuit & Waveforms

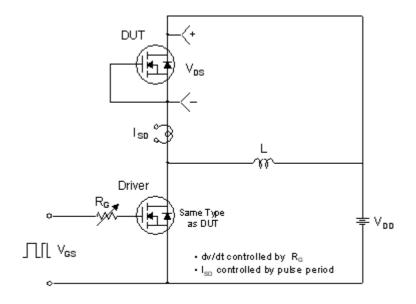


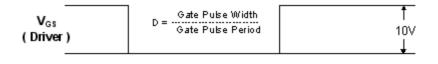
Unclamped Inductive Switching Test Circuit & Waveforms

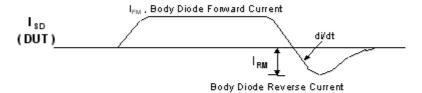


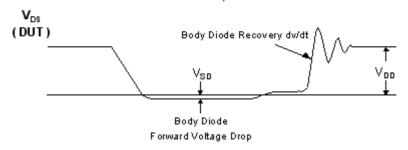


Peak Diode Recovery dv/dt Test Circuit & Waveforms



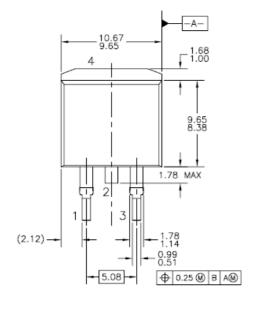


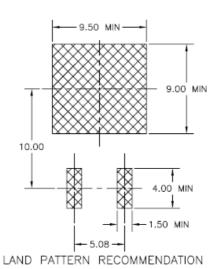




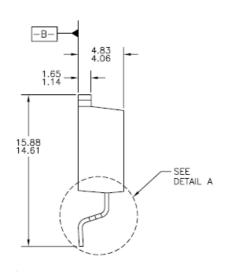
Mechanical Dimensions

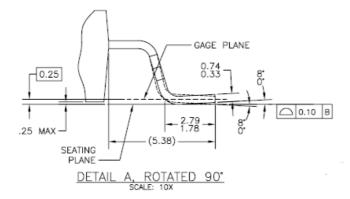
D² - PAK





6.22 MIN
6.86 MIN





Dimensions in Millimeters





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